

Supporting Information

Effects of surface characteristics of dielectric layers on polymer thin-film transistors obtained by spray methods

Hye-Yun Park,^a Jun-Su Jin,^b Sanggyu Yim,^b Seung-Hwan Oh,^c Phil-Hyun Kang,^c Si-Kyung Choi,^{a*} Sung-Yeon Jang^{b*}

Hye-Yun Park,^a Jun-Su Jin,^b Sanggyu Yim,^b Seung-Hwan Oh,^c Phil-Hyun Kang,^c Si-Kyung Choi,^{a} Sung-Yeon Jang^{b*}*

^a Department of Materials Science and Engineering, Korea Advanced Institute of Science and Technology, Daejeon 305-701, Republic of Korea

^b Department of Chemistry, Kookmin University, 861-1, Jeongneung-Dong, Seongbuk-Gu, Seoul 136-702, Republic of Korea

^c Radiation Research Division for Industry and Environment, Korea Atomic Energy Research Institute (KAERI), 29 Geumgu-gil, Jeongeup-si, Jeollabuk-do 580-185, Korea

*Corresponding Author. Tel/Fax: +82-(2)-910-5768/4415

E-mail address: syjang@kookmin.ac.kr

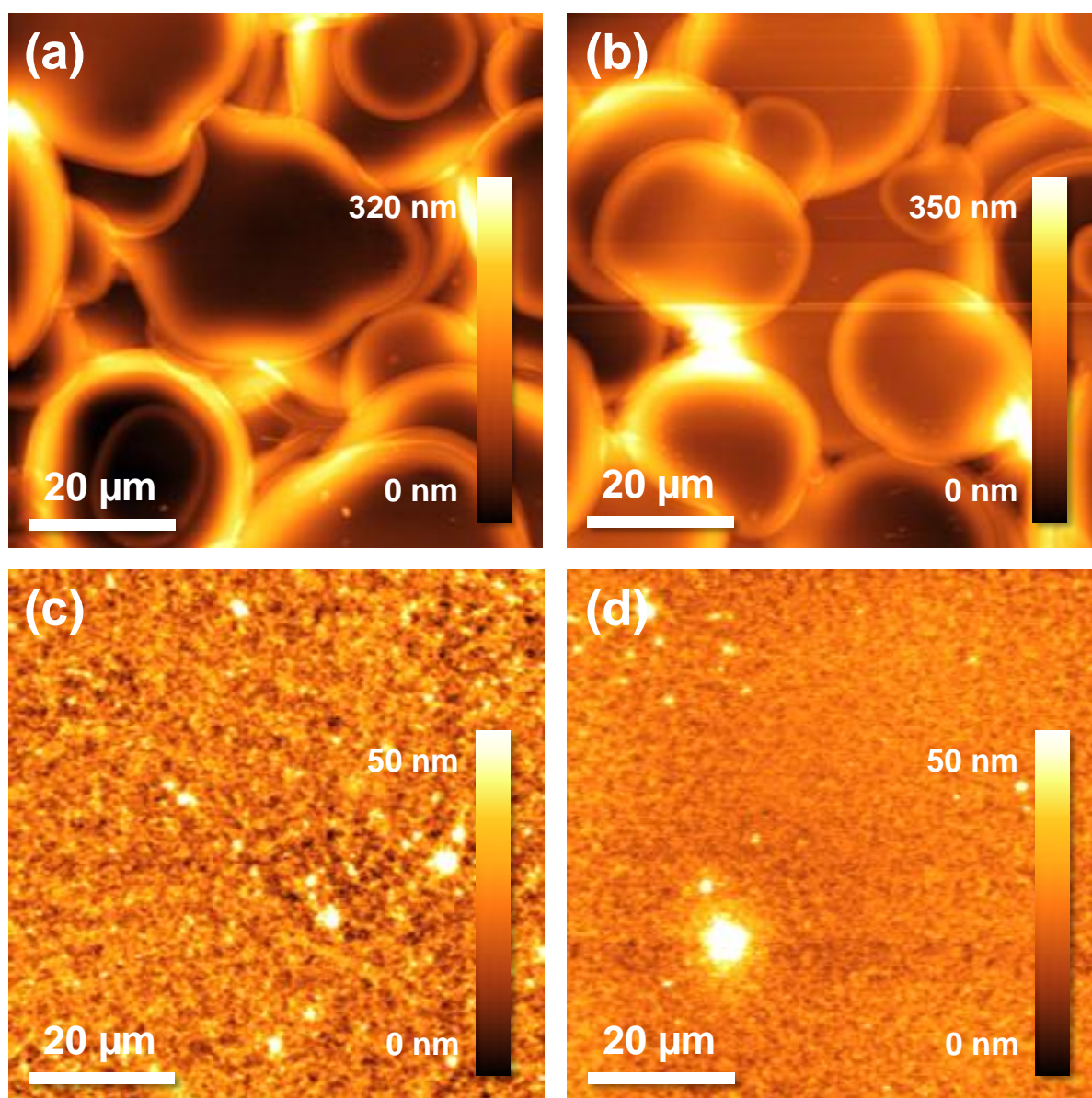


Figure S1. Contact mode AFM images of (a) as-sprayed P3HT films on the OTS/SiO₂ (b) as-sprayed P3HT films on the SiO₂ (c) SSO treated P3HT films on the OTS/SiO₂ and (d) SSO treated P3HT films on the SiO₂.

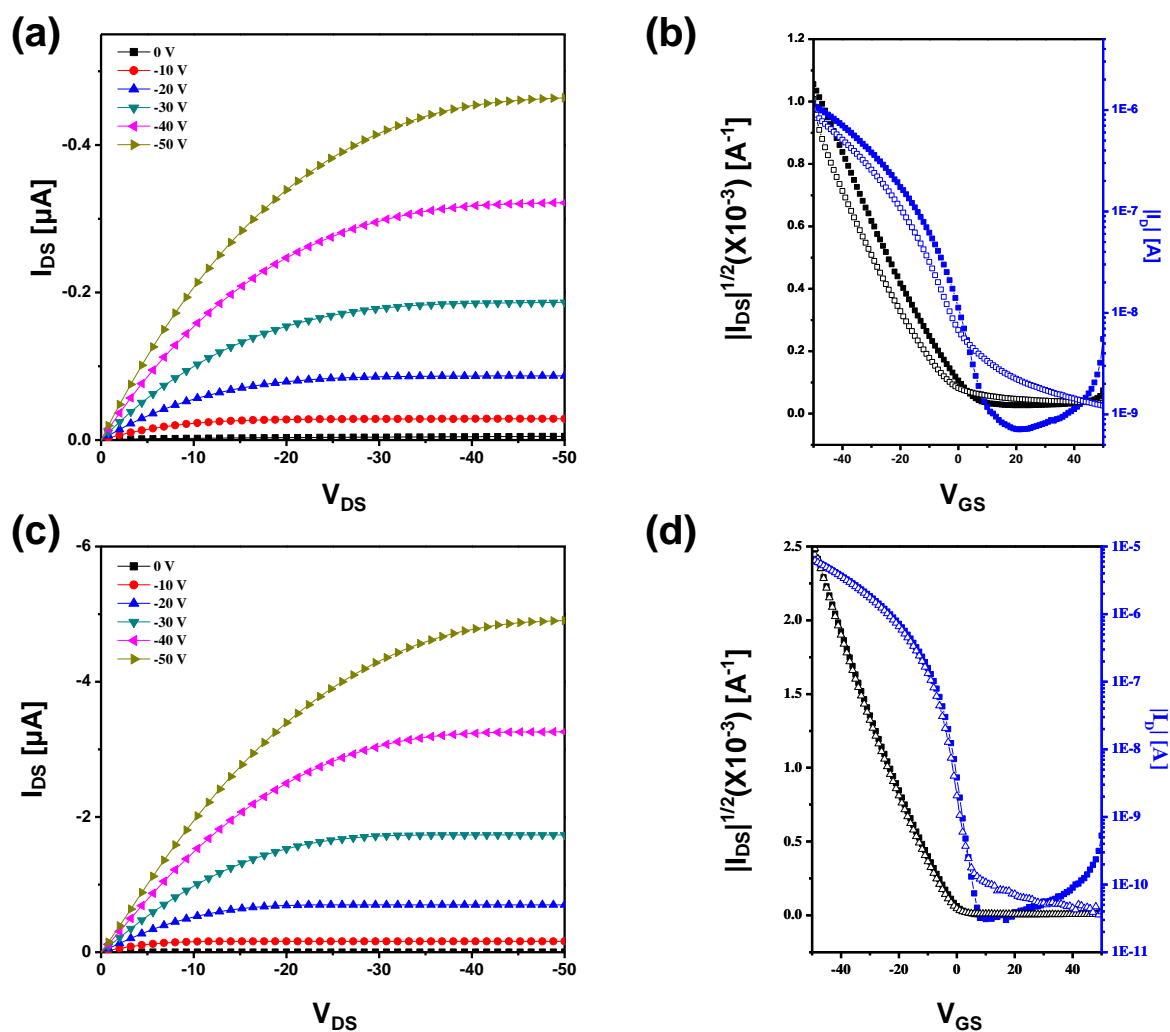


Figure S2. Output curve of (a) as-sprayed OFET on the OTS/SiO₂, (c) SSO treated OFET on the OTS/SiO₂. Transfer curve of (b) as-sprayed OFET on the OTS/SiO₂, (d) SSO treated OFET on the OTS/SiO₂. The closed symbol in transfer curve was obtained the forward scans and open symbols, backward scans.

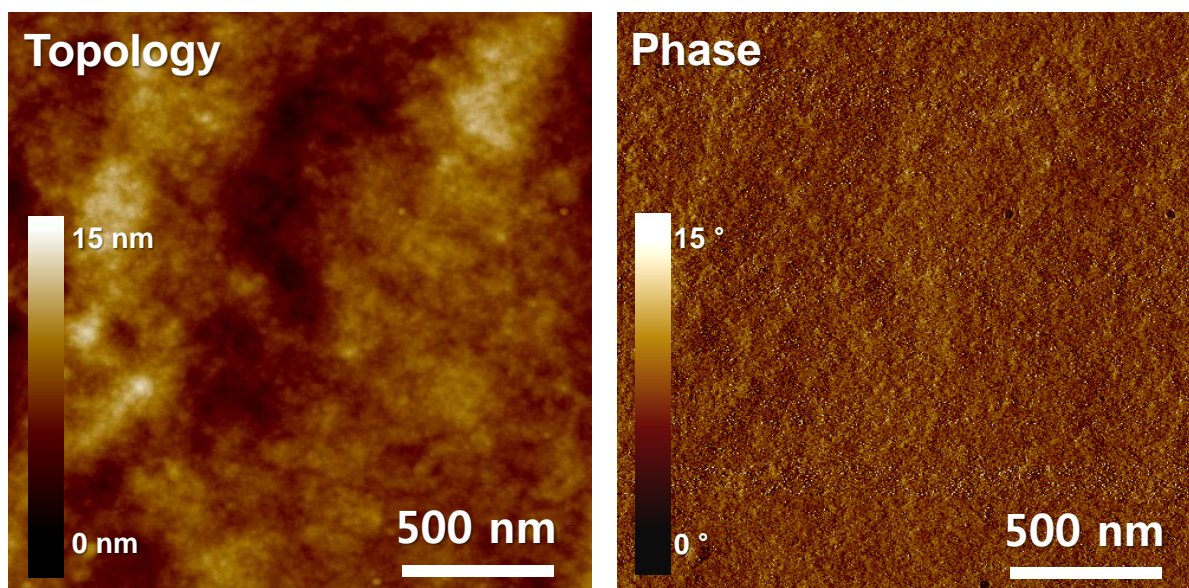


Figure S3. TM-AFM images of as sprayed P3HT on the OTS/SiO₂